

Notice of References Cited

Application/Control No.

10/064,690

Applicant(s)/Patent Under

Reexamination

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Examiner

Phung T Nguyen

Art Unit

2632

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,522,960	02-2003	Nada, Mitsuhiro	701/22
	B	US-			
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	D	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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